



Image # AFK 823

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Hiroaki Niimi, et al.

Art Unit: 2823

Serial No.: 09/885,744

Examiner: Khiem D. Nguyen

Filed: 06/20/01

Docket: TI-32705

For: Method for Annealing Ultra-Thin, High Quality Gate Oxide Layers Using Oxidizer/Hydrogen Mixtures

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Dear Sir:

MAILING CERTIFICATE UNDER 37 C.F.R. §1.8(A)  
I hereby certify that the above correspondence is being deposited with the U.S. Postal Service on 2-16-04 as First Class Mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

Karen Vertz

2-16-04

Karen Vertz

Date

EXTENSION OF TIME

Pursuant to 37 CFR 1.136(a), Applicants respectfully petition the Commissioner for an extension of the shortened statutory period for response in the above-identified Application.

The fee for this extension is indicated below:

- ☒ First Month (\$110)  
☐ Second Month (\$420)  
☐ Third Month (\$950)  
☐ Fourth Month (\$1,480)  
☐ Fifth Month (\$2,010)

Please charge the fee to deposit account No. 20-0668 of Texas Instruments Incorporated. The Commissioner is hereby authorized to charge any fees which may be required, or credit any overpayment to Account No. 20-0668. An original and two copies of this sheet are enclosed

Respectfully submitted

Gary C. Honeycutt  
Gary C. Honeycutt  
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